


<b>Search Notes</b>  	<b>Application/Control No.</b>  10665725	<b>Applicant(s)/Patent Under Reexamination</b>  LIEW ET AL.
	<b>Examiner</b>  JOHN F RAMIREZ	<b>Art Unit</b>  3737

SEARCHED			
Class	Subclass	Date	Examiner
382	128	2/26/08	JFR
600	407,410	2/27/08	JFR

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor's name	2/27/08	JFR
Backward/forward citations	2/27/08	JFR

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner